

Test Plot 1#:Measurement Report for GSM 850, CHEEK, GSM 850 UID 10021 DAC, Channel 190 (836.600MHz)

Device under Test Properties

Model, Manufacturer	Dimensions [mm]	IMEI	DUT Type
V2000	136.0 x 56.0 x 14.0		4G Feature Phone

Exposure Conditions

Phantom Section, TSL	Position, Test Distance [mm]	Band	Group, UID	Frequency [MHz], Channel Number	Conversion Factor	TSL Conductivity [S/m]	TSL Permittivity
RightHead, HSL	CHEEK, 0.00	GSM 850	GSM, 10021-DAC	836.600, 190	9.4	0.931	42.2

Hardware Setup

Phantom	TSL, Measured Date	Probe, Calibration Date	DAE, Calibration Date
Twin-SAM V8.0 (30deg probe tilt) - 2124	HBBL600-10000V6220420-1, 2025-December-21	EX3DV4 - SN7896, 2025-12-11	DAE4 Sn1724, 2025-03-14

Scan Setup

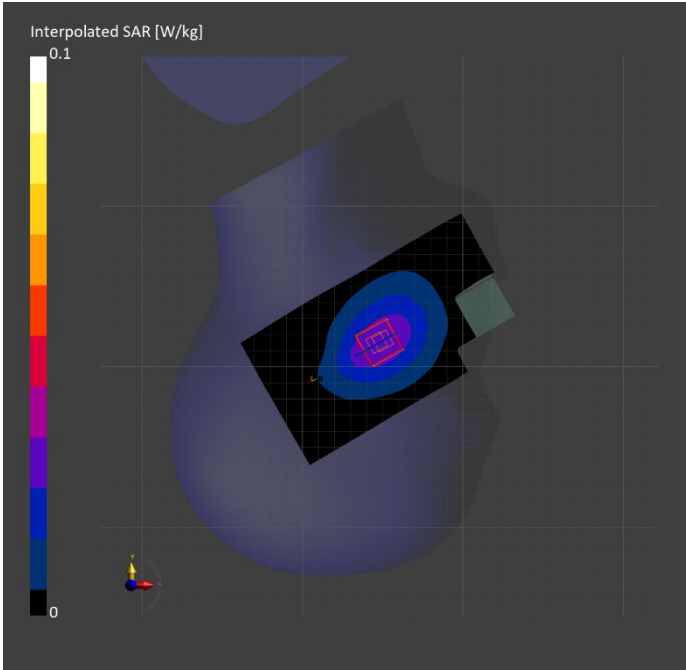
	Area Scan	Zoom Scan
Grid Extents [mm]	90.0 x 180.0	30.0 x 30.0 x 30.0
Grid Steps [mm]	15.0 x 15.0	6.0 x 6.0 x 1.5
Sensor Surface [mm]	3.0	1.4
Graded Grid	N/A	Yes
Grading Ratio	N/A	1.5
MAIA	Y	Y
Surface Detection	VMS + 6p	VMS + 6p
Scan Method	Measured	Measured

Measurement Results

	Area Scan	Zoom Scan
Date	2025-12-21, 17:40	2025-12-21, 17:50
psSAR1g [W/kg]	0.028	0.030
psSAR10g [W/kg]	0.019	0.025
Power Drift [dB]	0.04	0.15
Power Scaling	Disabled	Disabled
Scaling Factor [dB]		
TSL Correction	No correction	No correction
M2/M1 [%]		91.1
Dist 3dB Peak [mm]		20.9

Warning(s) / Error(s)

Details	Area Scan	Zoom Scan
Warning(s)		
Error(s)		



Test Plot 2#:Measurement Report for GSM 850, BACK, GSM 850 UID 10090 DAC, Channel 190 (836.600MHz)

Device under Test Properties

Model, Manufacturer	Dimensions [mm]	IMEI	DUT Type
V2000	136.0 x 56.0 x 14.0		4G Feature Phone

Exposure Conditions

Phantom Section, TSL	Position, Test Distance [mm]	Band	Group, UID	Frequency [MHz], Channel Number	Conversion Factor	TSL Conductivity [S/m]	TSL Permittivity
Flat, HSL	BACK, 5.00	GSM 850	GSM, 10090-DAC	836.600, 190	9.4	0.931	42.2

Hardware Setup

Phantom	TSL, Measured Date	Probe, Calibration Date	DAE, Calibration Date
Twin-SAM V8.0 (30deg probe tilt) - 2124	HBBL600-10000V6220420-1, 2025-December-21	EX3DV4 - SN7896, 2025-12-11	DAE4 Sn1724, 2025-03-14

Scan Setup

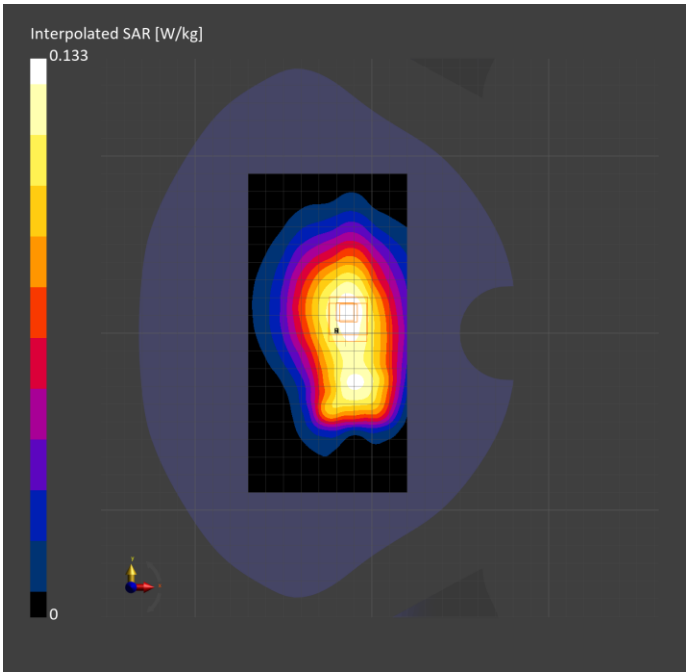
	Area Scan	Zoom Scan
Grid Extents [mm]	90.0 x 180.0	30.0 x 30.0 x 30.0
Grid Steps [mm]	15.0 x 15.0	6.0 x 6.0 x 1.5
Sensor Surface [mm]	3.0	1.4
Graded Grid	N/A	Yes
Grading Ratio	N/A	1.5
MAIA	Y	N/A
Surface Detection	All points	All points
Scan Method	Measured	Measured

Measurement Results

	Area Scan	Zoom Scan
Date	2025-12-21, 18:34	2025-12-21, 18:49
psSAR1g [W/kg]	0.095	0.104
psSAR10g [W/kg]	0.065	0.086
Power Drift [dB]	-0.08	0.08
Power Scaling	Disabled	Disabled
Scaling Factor [dB]		
TSL Correction	No correction	No correction
M2/M1 [%]		92.4
Dist 3dB Peak [mm]		> 15.0

Warning(s) / Error(s)

Details	Area Scan	Zoom Scan
Warning(s)		
Error(s)		



Test Plot 3#:Measurement Report for PCS 1900CHEEK, PCS 1900 UID 10021 DAC, Channel 661 (1880.000MHz)

Device under Test Properties

Model, Manufacturer	Dimensions [mm]	IMEI	DUT Type
V2000	136.0 x 56.0 x 14.0		4G Feature Phone

Exposure Conditions

Phantom Section, TSL	Position, Test Distance [mm]	Band	Group, UID	Frequency [MHz], Channel Number	Conversion Factor	TSL Conductivity [S/m]	TSL Permittivity
LeftHead, HSL	CHEEK, 0.00	PCS 1900	GSM, 10021-DAC	1880.000, 661	7.55	1.4455	41.2

Hardware Setup

Phantom	TSL, Measured Date	Probe, Calibration Date	DAE, Calibration Date
Twin-SAM V8.0 (30deg probe tilt) - 2124	HBBL600-10000V6220420-1, 2025-December-25	EX3DV4 - SN7896, 2025-12-11	DAE4 Sn1724, 2025-03-14

Scan Setup

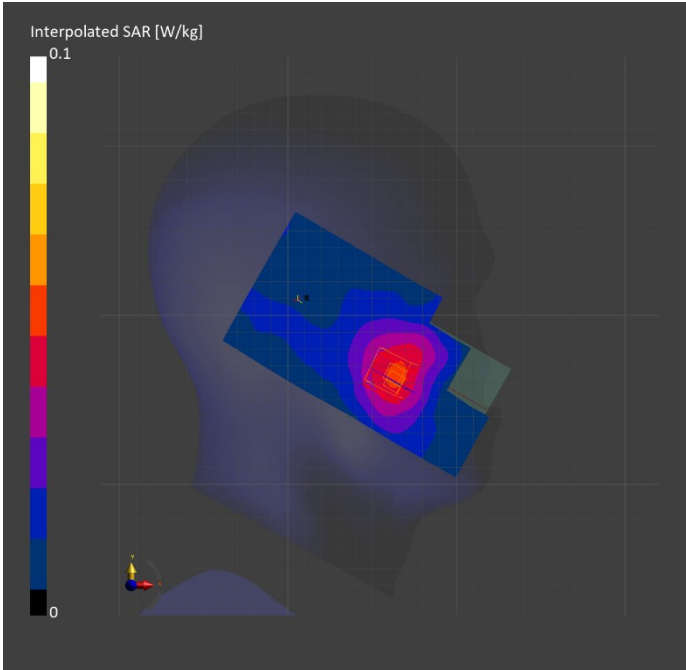
	Area Scan	Zoom Scan
Grid Extents [mm]	90.0 x 180.0	30.0 x 30.0 x 30.0
Grid Steps [mm]	15.0 x 15.0	6.0 x 6.0 x 1.5
Sensor Surface [mm]	3.0	1.4
Graded Grid	N/A	Yes
Grading Ratio	N/A	1.5
MAIA	Y	Y
Surface Detection	VMS + 6p	VMS + 6p
Scan Method	Measured	Measured

Measurement Results

	Area Scan	Zoom Scan
Date	2025-12-25, 10:01	2025-12-25, 10:15
psSAR1g [W/kg]	0.044	0.048
psSAR10g [W/kg]	0.027	0.040
Power Drift [dB]	0.02	0.01
Power Scaling	Disabled	Disabled
Scaling Factor [dB]		
TSL Correction	No correction	No correction
M2/M1 [%]		87.7
Dist 3dB Peak [mm]		22.9

Warning(s) / Error(s)

Details	Area Scan	Zoom Scan
Warning(s)		
Error(s)		



Test Plot 4#:Measurement Report for PCS 1900, BACK, PCS 1900 UID 10021 DAC, Channel 661 (1880.000MHz)

Device under Test Properties

Model, Manufacturer	Dimensions [mm]	IMEI	DUT Type
V2000	136.0 x 56.0 x 14.0		4G Feature Phone

Exposure Conditions

Phantom Section, TSL	Position, Test Distance [mm]	Band	Group, UID	Frequency [MHz], Channel Number	Conversion Factor	TSL Conductivity [S/m]	TSL Permittivity
Flat, HSL	BACK, 5.00	PCS 1900	GSM, 10021-DAC	1880.000, 661	7.55	1.4455	41.2

Hardware Setup

Phantom	TSL, Measured Date	Probe, Calibration Date	DAE, Calibration Date
Twin-SAM V8.0 (30deg probe tilt) - 2124	HBBL600-10000V6220420-1, 2025-December-25	EX3DV4 - SN7896, 2025-12-11	DAE4 Sn1724, 2025-03-14

Scan Setup

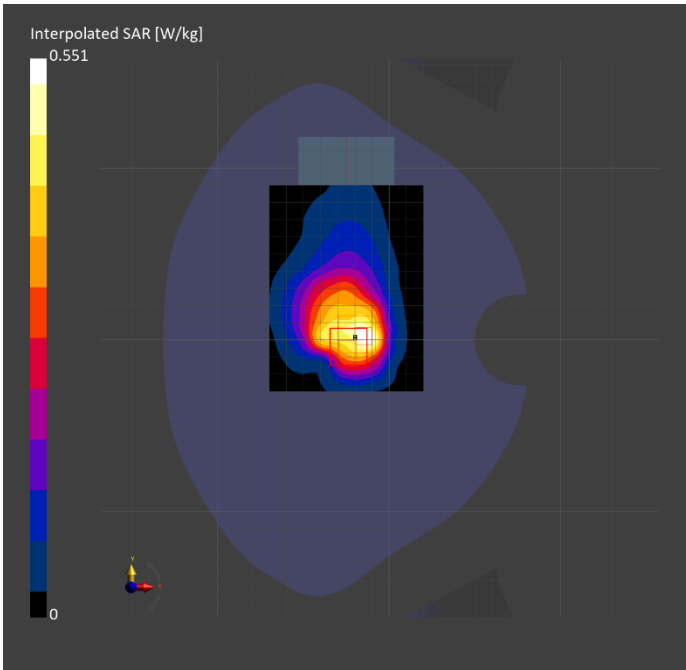
	Area Scan	Zoom Scan
Grid Extents [mm]	90.0 x 120.0	30.0 x 30.0 x 30.0
Grid Steps [mm]	15.0 x 15.0	5.4 x 5.4 x 1.5
Sensor Surface [mm]	3.0	1.4
Graded Grid	N/A	Yes
Grading Ratio	N/A	1.5
MAIA	N/A	N/A
Surface Detection	All points	All points
Scan Method	Measured	Measured

Measurement Results

	Area Scan	Zoom Scan
Date	2025-12-25, 10:16	2025-12-25, 10:34
psSAR1g [W/kg]	0.229	0.257
psSAR10g [W/kg]	0.131	0.146
Power Drift [dB]	-0.08	-0.18
Power Scaling	Disabled	Disabled
Scaling Factor [dB]		
TSL Correction	No correction	No correction
M2/M1 [%]		74.9
Dist 3dB Peak [mm]		6.2

Warning(s) / Error(s)

Details	Area Scan	Zoom Scan
Warning(s)		
Error(s)		



Test Plot 5#:Measurement Report for WCDMA Band 2, CHEEK, Band 2, UID 10457 AAB, Channel 9400 (1880.000MHz)

Device under Test Properties

Model, Manufacturer	Dimensions [mm]	IMEI	DUT Type
V2000	136.0 x 56.0 x 14.0		4G Feature Phone

Exposure Conditions

Phantom Section, TSL	Position, Test Distance [mm]	Band	Group, UID	Frequency [MHz], Channel Number	Conversion Factor	TSL Conductivity [S/m]	TSL Permittivity
LeftHead, HSL	CHEEK, 0.00	Band 2	WCDMA, 10457-AAB	1880.000, 9400	7.55	1.4455	41.2

Hardware Setup

Phantom	TSL, Measured Date	Probe, Calibration Date	DAE, Calibration Date
Twin-SAM V8.0 (30deg probe tilt) - 2124	HBBL600-10000V6220420-1, 2025-December-25	EX3DV4 - SN7896, 2025-12-11	DAE4 Sn1724, 2025-03-14

Scan Setup

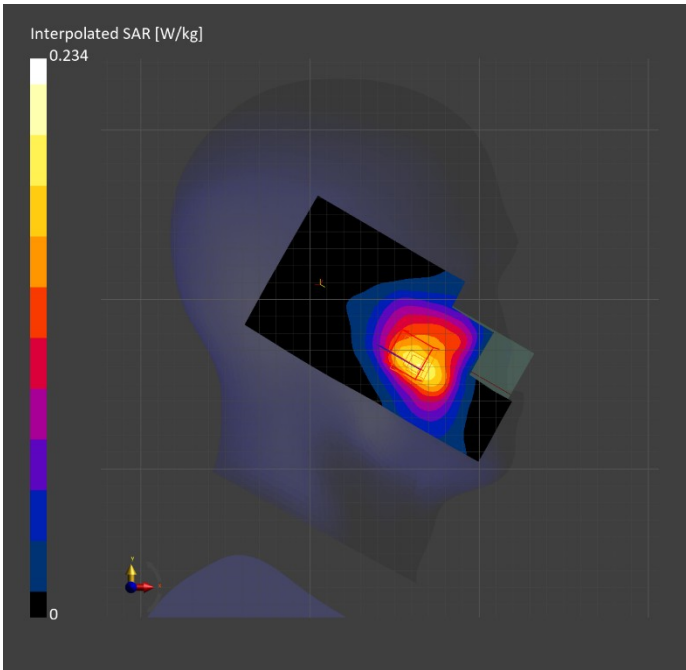
	Area Scan	Zoom Scan
Grid Extents [mm]	90.0 x 180.0	30.0 x 30.0 x 30.0
Grid Steps [mm]	15.0 x 15.0	6.0 x 6.0 x 1.5
Sensor Surface [mm]	3.0	1.4
Graded Grid	N/A	Yes
Grading Ratio	N/A	1.5
MAIA	Y	N/A
Surface Detection	VMS + 6p	VMS + 6p
Scan Method	Measured	Measured

Measurement Results

	Area Scan	Zoom Scan
Date	2025-12-25, 03:03	2025-12-25, 03:17
psSAR1g [W/kg]	0.159	0.183
psSAR10g [W/kg]	0.094	0.131
Power Drift [dB]	-0.03	0.19
Power Scaling	Disabled	Disabled
Scaling Factor [dB]		
TSL Correction	No correction	No correction
M2/M1 [%]		91.7
Dist 3dB Peak [mm]		13.4

Warning(s) / Error(s)

Details	Area Scan	Zoom Scan
Warning(s)		
Error(s)		



Test Plot 6#:Measurement Report for WCDMA Band 2, BACK, Band 2, UID 10457 AAB, Channel 9262 (1852.400MHz)

Device under Test Properties

Model, Manufacturer	Dimensions [mm]	IMEI	DUT Type
V2000	136.0 x 56.0 x 14.0		4G Feature Phone

Exposure Conditions

Phantom Section, TSL	Position, Test Distance [mm]	Band	Group, UID	Frequency [MHz], Channel Number	Conversion Factor	TSL Conductivity [S/m]	TSL Permittivity
Flat, HSL	BACK, 5.00	Band 2	WCDMA, 10457-AAB	1852.400, 9262	7.55	1.462	41.0

Hardware Setup

Phantom	TSL, Measured Date	Probe, Calibration Date	DAE, Calibration Date
Twin-SAM V8.0 (30deg probe tilt) - 2124	HBBL600-10000V6220420-1, 2025-December-25	EX3DV4 - SN7896, 2025-12-11	DAE4 Sn1724, 2025-03-14

Scan Setup

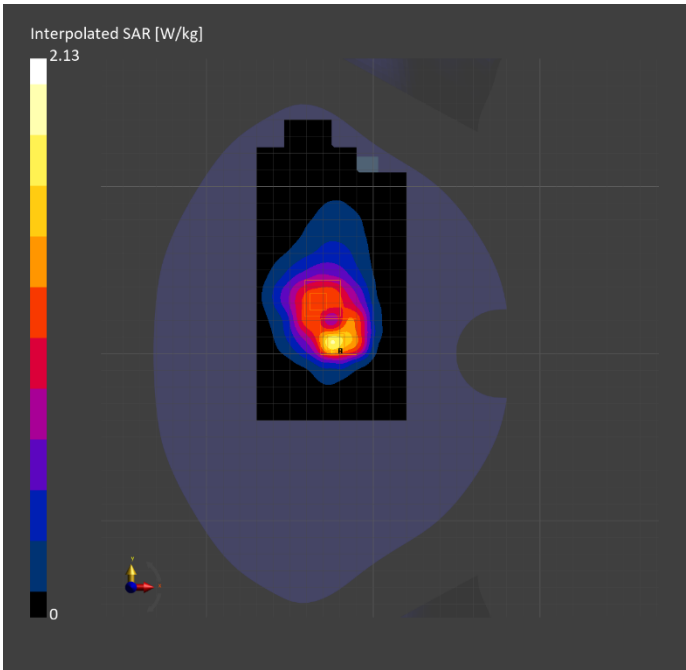
	Area Scan	Zoom Scan
Grid Extents [mm]	90.0 x 180.0	30.0 x 30.0 x 30.0
Grid Steps [mm]	15.0 x 15.0	6.0 x 6.0 x 1.5
Sensor Surface [mm]	3.0	1.4
Graded Grid	N/A	Yes
Grading Ratio	N/A	1.5
MAIA	N/A	N/A
Surface Detection	VMS + 6p	VMS + 6p
Scan Method	Measured	Measured

Measurement Results

	Area Scan	Zoom Scan
Date	2025-12-25, 02:24	2025-12-25, 02:50
psSAR1g [W/kg]	1.26	1.08
psSAR10g [W/kg]	0.741	0.747
Power Drift [dB]	0.01	-0.02
Power Scaling	Disabled	Disabled
Scaling Factor [dB]		
TSL Correction	No correction	No correction
M2/M1 [%]		81.4
Dist 3dB Peak [mm]		14.5

Warning(s) / Error(s)

Details	Area Scan	Zoom Scan
Warning(s)		
Error(s)		



Test Plot 7#:Measurement Report for WCDMA Band 4, CHEEK, Band 4, UID 10011 AAB, Channel 1413 (1732.600MHz)

Device under Test Properties

Model, Manufacturer	Dimensions [mm]	IMEI	DUT Type
V2000	136.0 x 56.0 x 14.0		4G Feature Phone

Exposure Conditions

Phantom Section, TSL	Position, Test Distance [mm]	Band	Group, UID	Frequency [MHz], Channel Number	Conversion Factor	TSL Conductivity [S/m]	TSL Permittivity
LeftHead, HSL	CHEEK, 0.00	Band 4	WCDMA, 10011-AAB	1732.600, 1413	7.89	1.363	41.1

Hardware Setup

Phantom	TSL, Measured Date	Probe, Calibration Date	DAE, Calibration Date
Twin-SAM V8.0 (30deg probe tilt) - 2124	HBBL600-10000V6220420-1, 2025-December-23	EX3DV4 - SN7896, 2025-12-11	DAE4 Sn1724, 2025-03-14

Scan Setup

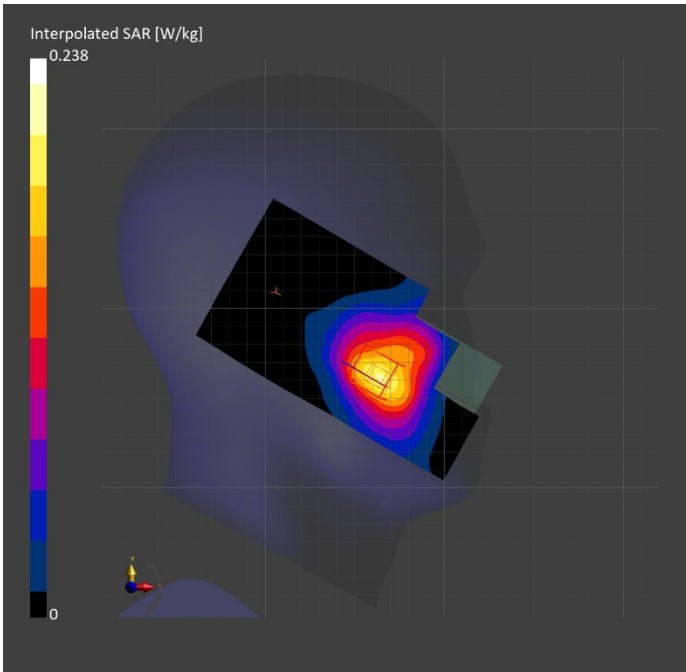
	Area Scan	Zoom Scan
Grid Extents [mm]	90.0 x 180.0	30.0 x 30.0 x 30.0
Grid Steps [mm]	15.0 x 15.0	6.0 x 6.0 x 1.5
Sensor Surface [mm]	3.0	1.4
Graded Grid	N/A	Yes
Grading Ratio	N/A	1.5
MAIA	Y	N/A
Surface Detection	VMS + 6p	VMS + 6p
Scan Method	Measured	Measured

Measurement Results

	Area Scan	Zoom Scan
Date	2025-12-23, 08:27	2025-12-23, 08:41
psSAR1g [W/kg]	0.166	0.183
psSAR10g [W/kg]	0.100	0.137
Power Drift [dB]	-0.03	0.12
Power Scaling	Disabled	Disabled
Scaling Factor [dB]		
TSL Correction	No correction	No correction
M2/M1 [%]		91.4
Dist 3dB Peak [mm]		13.7

Warning(s) / Error(s)

Details	Area Scan	Zoom Scan
Warning(s)		
Error(s)		



Test Plot 8#:Measurement Report for WCDMA Band 4, BACK, Band 4, UID 10460 AAB, Channel 1312 (1712.400MHz)

Device under Test Properties

Model, Manufacturer	Dimensions [mm]	IMEI	DUT Type
V2000	136.0 x 56.0 x 14.0		4G Feature Phone

Exposure Conditions

Phantom Section, TSL	Position, Test Distance [mm]	Band	Group, UID	Frequency [MHz], Channel Number	Conversion Factor	TSL Conductivity [S/m]	TSL Permittivity
Flat, HSL	BACK, 5.00	Band 4	WCDMA, 10460-AAB	1712.400, 1312	7.89	1.381	40.7

Hardware Setup

Phantom	TSL, Measured Date	Probe, Calibration Date	DAE, Calibration Date
Twin-SAM V8.0 (30deg probe tilt) - 2124	HBBL600-10000V6220420-1, 2025-December-23	EX3DV4 - SN7896, 2025-12-11	DAE4 Sn1724, 2025-03-14

Scan Setup

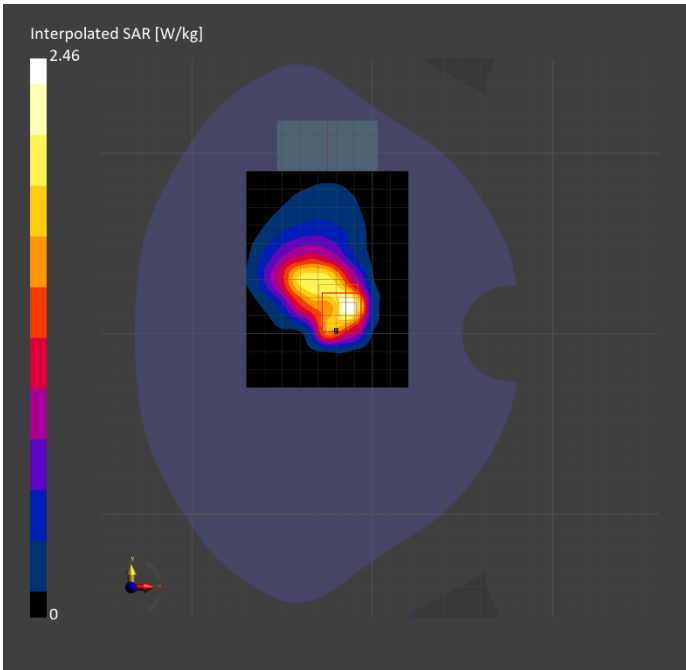
	Area Scan	Zoom Scan
Grid Extents [mm]	90.0 x 120.0	30.0 x 30.0 x 30.0
Grid Steps [mm]	15.0 x 15.0	6.0 x 6.0 x 1.5
Sensor Surface [mm]	3.0	1.4
Graded Grid	N/A	Yes
Grading Ratio	N/A	1.5
MAIA	N/A	N/A
Surface Detection	All points	All points
Scan Method	Measured	Measured

Measurement Results

	Area Scan	Zoom Scan
Date	2025-12-23, 01:39	2025-12-23, 02:09
psSAR1g [W/kg]	0.992	1.09
psSAR10g [W/kg]	0.557	0.625
Power Drift [dB]	-0.03	0.17
Power Scaling	Disabled	Disabled
Scaling Factor [dB]		
TSL Correction	No correction	No correction
M2/M1 [%]		71.8
Dist 3dB Peak [mm]		8.5

Warning(s) / Error(s)

Details	Area Scan	Zoom Scan
Warning(s)		
Error(s)		



Test Plot 9#:Measurement Report for WCDMA Band 5, CHEEK, Band 5, UID 10457 AAB, Channel 4183 (836.600MHz)

Device under Test Properties

Model, Manufacturer	Dimensions [mm]	IMEI	DUT Type
V2000	136.0 x 56.0 x 14.0		4G Feature Phone

Exposure Conditions

Phantom Section, TSL	Position, Test Distance [mm]	Band	Group, UID	Frequency [MHz], Channel Number	Conversion Factor	TSL Conductivity [S/m]	TSL Permittivity
LeftHead, HSL	CHEEK, 0.00	Band 5	WCDMA, 10457-AAB	836.600, 4183	9.4	0.931	42.2

Hardware Setup

Phantom	TSL, Measured Date	Probe, Calibration Date	DAE, Calibration Date
Twin-SAM V8.0 (30deg probe tilt) - 2124	HBBL600-10000V6220420-1, 2025-December-21	EX3DV4 - SN7896, 2025-12-11	DAE4 Sn1724, 2025-03-14

Scan Setup

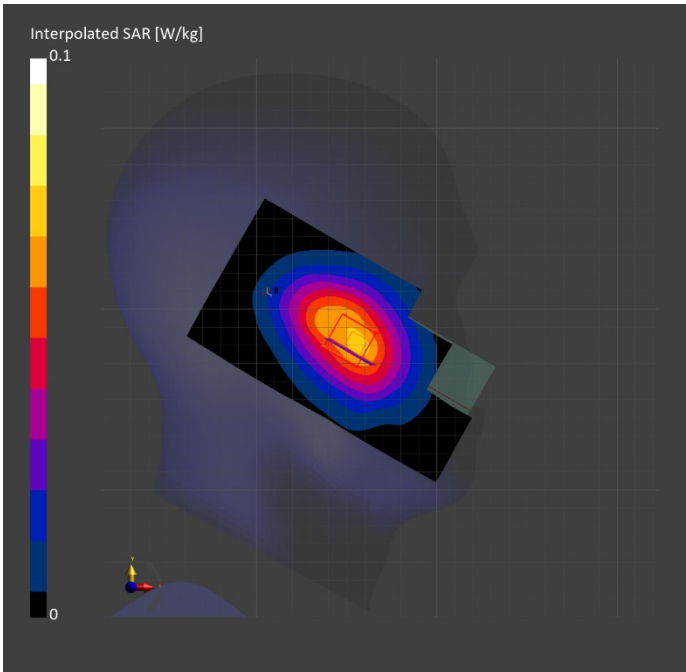
	Area Scan	Zoom Scan
Grid Extents [mm]	90.0 x 180.0	30.0 x 30.0 x 30.0
Grid Steps [mm]	15.0 x 15.0	6.0 x 6.0 x 1.5
Sensor Surface [mm]	3.0	1.4
Graded Grid	N/A	Yes
Grading Ratio	N/A	1.5
MAIA	Y	Y
Surface Detection	VMS + 6p	VMS + 6p
Scan Method	Measured	Measured

Measurement Results

	Area Scan	Zoom Scan
Date	2025-12-21, 06:26	2025-12-21, 06:37
psSAR1g [W/kg]	0.061	0.062
psSAR10g [W/kg]	0.041	0.048
Power Drift [dB]	0.14	0.08
Power Scaling	Disabled	Disabled
Scaling Factor [dB]		
TSL Correction	No correction	No correction
M2/M1 [%]		87.3
Dist 3dB Peak [mm]		22.0

Warning(s) / Error(s)

Details	Area Scan	Zoom Scan
Warning(s)		
Error(s)		



Test Plot 10#:Measurement Report for WCDMA Band 5, BACK, Band 5, UID 10457 AAB, Channel 4183 (836.600MHz)

Device under Test Properties

Model, Manufacturer	Dimensions [mm]	IMEI	DUT Type
V2000	136.0 x 56.0 x 14.0		4G Feature Phone

Exposure Conditions

Phantom Section, TSL	Position, Test Distance [mm]	Band	Group, UID	Frequency [MHz], Channel Number	Conversion Factor	TSL Conductivity [S/m]	TSL Permittivity
Flat, HSL	BACK, 5.00	Band 5	WCDMA, 10457-AAB	836.600, 4183	9.4	0.931	42.2

Hardware Setup

Phantom	TSL, Measured Date	Probe, Calibration Date	DAE, Calibration Date
Twin-SAM V8.0 (30deg probe tilt) - 2124	HBBL600-10000V6220420-1, 2025-December-21	EX3DV4 - SN7896, 2025-12-11	DAE4 Sn1724, 2025-03-14

Scan Setup

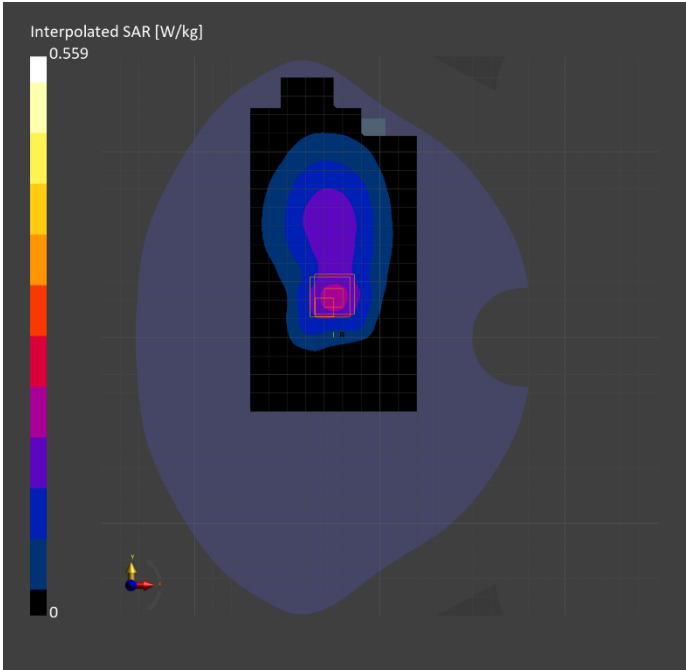
	Area Scan	Zoom Scan
Grid Extents [mm]	90.0 x 180.0	30.0 x 30.0 x 30.0
Grid Steps [mm]	15.0 x 15.0	6.0 x 6.0 x 1.5
Sensor Surface [mm]	3.0	1.4
Graded Grid	N/A	Yes
Grading Ratio	N/A	1.5
MAIA	N/A	N/A
Surface Detection	All points	All points
Scan Method	Measured	Measured

Measurement Results

	Area Scan	Zoom Scan
Date	2025-12-21, 07:37	2025-12-21, 08:11
psSAR1g [W/kg]	0.187	0.218
psSAR10g [W/kg]	0.116	0.121
Power Drift [dB]	0.16	0.04
Power Scaling	Disabled	Disabled
Scaling Factor [dB]		
TSL Correction	No correction	No correction
M2/M1 [%]		66.5
Dist 3dB Peak [mm]		8.1

Warning(s) / Error(s)

Details	Area Scan	Zoom Scan
Warning(s)		
Error(s)		



Test Plot 11#:Measurement Report for LTE Band 2, CHEEK, Band 2, UID 10169 CAF, Channel 18900 (1880.000MHz)

Device under Test Properties

Model, Manufacturer	Dimensions [mm]	IMEI	DUT Type
V2000	136.0 x 56.0 x 14.0		4G Feature Phone

Exposure Conditions

Phantom Section, TSL	Position, Test Distance [mm]	Band	Group, UID	Frequency [MHz], Channel Number	Conversion Factor	TSL Conductivity [S/m]	TSL Permittivity
RightHead, HSL	CHEEK, 0.00	Band 2	LTE-FDD, 10169-CAF	1880.000, 18900	7.55	1.445	41.4

Hardware Setup

Phantom	TSL, Measured Date	Probe, Calibration Date	DAE, Calibration Date
Twin-SAM V8.0 (30deg probe tilt) - 2124	HBBL600-10000V6220420-1, 2025-December-25	EX3DV4 - SN7896, 2025-12-11	DAE4 Sn1724, 2025-03-14

Scan Setup

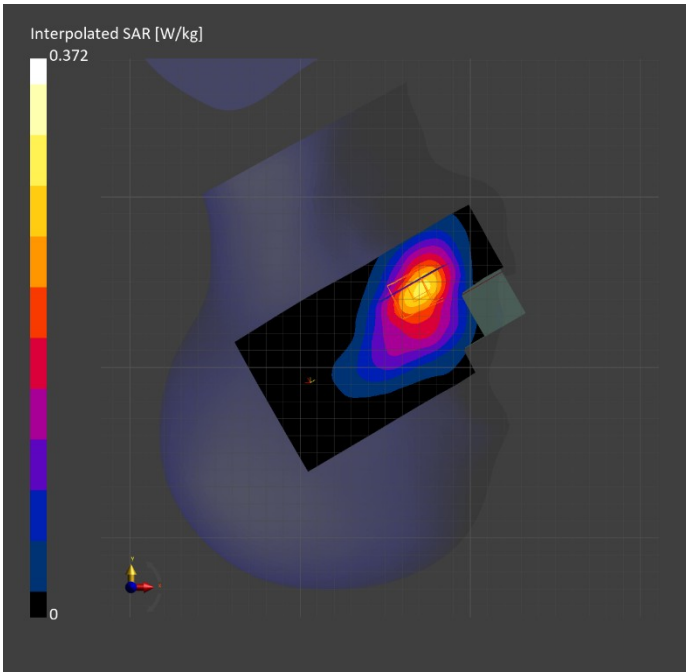
	Area Scan	Zoom Scan
Grid Extents [mm]	90.0 x 180.0	30.0 x 30.0 x 30.0
Grid Steps [mm]	15.0 x 15.0	6.0 x 6.0 x 1.5
Sensor Surface [mm]	3.0	1.4
Graded Grid	N/A	Yes
Grading Ratio	N/A	1.5
MAIA	N/A	N/A
Surface Detection	VMS + 6p	All points
Scan Method	Measured	Measured

Measurement Results

	Area Scan	Zoom Scan
Date	2025-12-25, 12:06	2025-12-25, 12:29
psSAR1g [W/kg]	0.235	0.264
psSAR10g [W/kg]	0.137	0.185
Power Drift [dB]	0.04	-0.04
Power Scaling	Disabled	Disabled
Scaling Factor [dB]		
TSL Correction	No correction	No correction
M2/M1 [%]		89.5
Dist 3dB Peak [mm]		13.2

Warning(s) / Error(s)

Details	Area Scan	Zoom Scan
Warning(s)		
Error(s)		



Test Plot 12#:Measurement Report for LTE Band 2, BACK, Band 2, UID 10169 CAF, Channel 18900 (1880.000MHz)

Device under Test Properties

Model, Manufacturer	Dimensions [mm]	IMEI	DUT Type
V2000	136.0 x 56.0 x 14.0		4G Feature Phone

Exposure Conditions

Phantom Section, TSL	Position, Test Distance [mm]	Band	Group, UID	Frequency [MHz], Channel Number	Conversion Factor	TSL Conductivity [S/m]	TSL Permittivity
Flat, HSL	BACK, 5.00	Band 2	LTE-FDD, 10169-CAF	1880.000, 18900	7.55	1.445	41.4

Hardware Setup

Phantom	TSL, Measured Date	Probe, Calibration Date	DAE, Calibration Date
Twin-SAM V8.0 (30deg probe tilt) - 2124	HBBL600-10000V6220420-1, 2025-December-25	EX3DV4 - SN7896, 2025-12-11	DAE4 Sn1724, 2025-03-14

Scan Setup

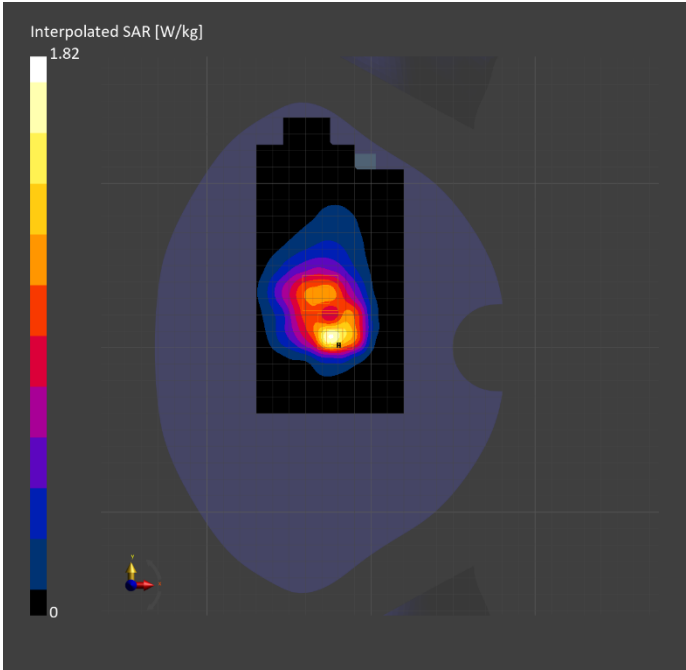
	Area Scan	Zoom Scan
Grid Extents [mm]	90.0 x 180.0	30.0 x 30.0 x 30.0
Grid Steps [mm]	15.0 x 15.0	6.0 x 6.0 x 1.5
Sensor Surface [mm]	3.0	1.4
Graded Grid	N/A	Yes
Grading Ratio	N/A	1.5
MAIA	N/A	N/A
Surface Detection	All points	All points
Scan Method	Measured	Measured

Measurement Results

	Area Scan	Zoom Scan
Date	2025-12-25, 09:27	2025-12-25, 09:59
psSAR1g [W/kg]	1.29	1.07
psSAR10g [W/kg]	0.692	0.683
Power Drift [dB]	0.05	-0.01
Power Scaling	Disabled	Disabled
Scaling Factor [dB]		
TSL Correction	No correction	No correction
M2/M1 [%]		78.7
Dist 3dB Peak [mm]		16.7

Warning(s) / Error(s)

Details	Area Scan	Zoom Scan
Warning(s)		
Error(s)		



Test Plot 13#:Measurement Report for LTE Band 5, CHEEK, Band 5, UID 10175 CAH, Channel 20525 (836.500MHz)

Device under Test Properties

Model, Manufacturer	Dimensions [mm]	IMEI	DUT Type
V2000	136.0 x 56.0 x 14.0		4G Feature Phone

Exposure Conditions

Phantom Section, TSL	Position, Test Distance [mm]	Band	Group, UID	Frequency [MHz], Channel Number	Conversion Factor	TSL Conductivity [S/m]	TSL Permittivity
LeftHead, HSL	CHEEK, 0.00	Band 5	LTE-FDD, 10175-CAH	836.500, 20525	9.4	0.931	42.2

Hardware Setup

Phantom	TSL, Measured Date	Probe, Calibration Date	DAE, Calibration Date
Twin-SAM V8.0 (30deg probe tilt) - 2124	HBBL600-10000V6220420-1, 2025-December-21	EX3DV4 - SN7896, 2025-12-11	DAE4 Sn1724, 2025-03-14

Scan Setup

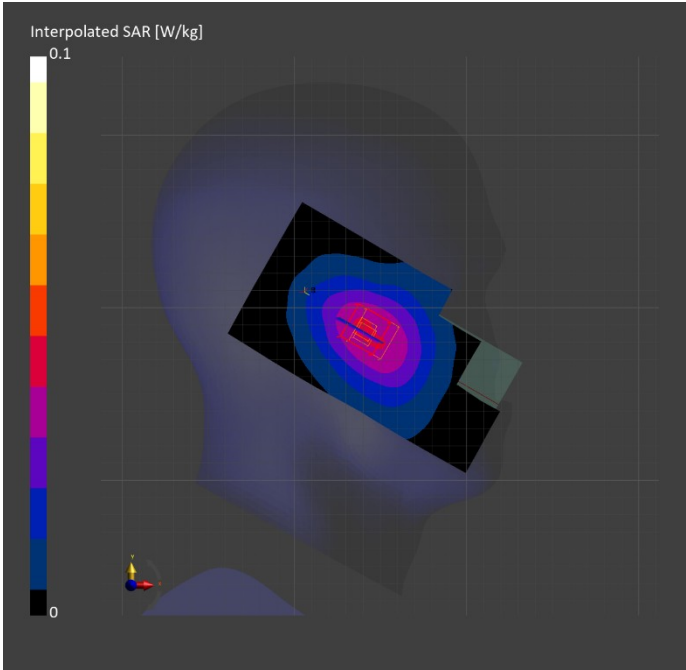
	Area Scan	Zoom Scan
Grid Extents [mm]	90.0 x 180.0	30.0 x 30.0 x 30.0
Grid Steps [mm]	15.0 x 15.0	6.0 x 6.0 x 1.5
Sensor Surface [mm]	3.0	1.4
Graded Grid	N/A	Yes
Grading Ratio	N/A	1.5
MAIA	Y	Y
Surface Detection	VMS + 6p	VMS + 6p
Scan Method	Measured	Measured

Measurement Results

	Area Scan	Zoom Scan
Date	2025-12-21, 06:48	2025-12-21, 06:58
psSAR1g [W/kg]	0.038	0.041
psSAR10g [W/kg]	0.026	0.034
Power Drift [dB]	-0.04	0.10
Power Scaling	Disabled	Disabled
Scaling Factor [dB]		
TSL Correction	No correction	No correction
M2/M1 [%]		93.4
Dist 3dB Peak [mm]		> 15.0

Warning(s) / Error(s)

Details	Area Scan	Zoom Scan
Warning(s)		
Error(s)		



Test Plot 14#:Measurement Report for LTE Band 5, BACK, Band 5, UID 10175 CAH, Channel 20525 (836.500MHz)

Device under Test Properties

Model, Manufacturer	Dimensions [mm]	IMEI	DUT Type
V2000	136.0 x 56.0 x 14.0		4G Feature Phone

Exposure Conditions

Phantom Section, TSL	Position, Test Distance [mm]	Band	Group, UID	Frequency [MHz], Channel Number	Conversion Factor	TSL Conductivity [S/m]	TSL Permittivity
Flat, HSL	BACK, 5.00	Band 5	LTE-FDD, 10175-CAH	836.500, 20525	9.4	0.931	42.2

Hardware Setup

Phantom	TSL, Measured Date	Probe, Calibration Date	DAE, Calibration Date
Twin-SAM V8.0 (30deg probe tilt) - 2124	HBBL600-10000V6220420-1, 2025-December-21	EX3DV4 - SN7896, 2025-12-11	DAE4 Sn1724, 2025-03-14

Scan Setup

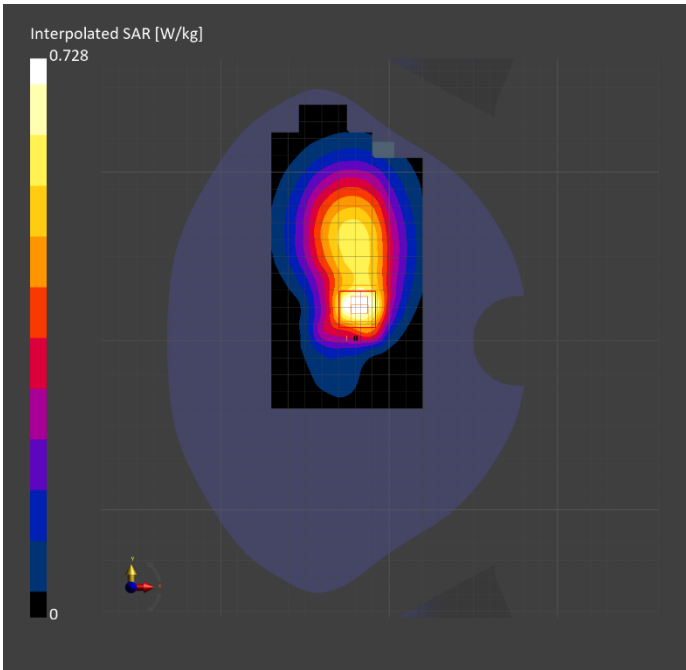
	Area Scan	Zoom Scan
Grid Extents [mm]	90.0 x 180.0	30.0 x 30.0 x 30.0
Grid Steps [mm]	15.0 x 15.0	6.0 x 6.0 x 1.5
Sensor Surface [mm]	3.0	1.4
Graded Grid	N/A	Yes
Grading Ratio	N/A	1.5
MAIA	N/A	N/A
Surface Detection	VMS + 6p	All points
Scan Method	Measured	Measured

Measurement Results

	Area Scan	Zoom Scan
Date	2025-12-21, 01:44	2025-12-21, 01:58
psSAR1g [W/kg]	0.225	0.280
psSAR10g [W/kg]	0.144	0.150
Power Drift [dB]	0.04	-0.08
Power Scaling	Disabled	Disabled
Scaling Factor [dB]		
TSL Correction	No correction	No correction
M2/M1 [%]		64.6
Dist 3dB Peak [mm]		9.4

Warning(s) / Error(s)

Details	Area Scan	Zoom Scan
Warning(s)		
Error(s)		



Test Plot 15#:Measurement Report for LTE Band 12, CHEEK, Band 12, UID 10175 CAH, Channel 23095 (707.500MHz)

Device under Test Properties

Model, Manufacturer	Dimensions [mm]	IMEI	DUT Type
V2000	136.0 x 56.0 x 14.0		4G Feature Phone

Exposure Conditions

Phantom Section, TSL	Position, Test Distance [mm]	Band	Group, UID	Frequency [MHz], Channel Number	Conversion Factor	TSL Conductivity [S/m]	TSL Permittivity
RightHead, HSL	CHEEK, 0.00	Band 12	LTE-FDD, 10175-CAH	707.500, 23095	9.4	0.899	42.6

Hardware Setup

Phantom	TSL, Measured Date	Probe, Calibration Date	DAE, Calibration Date
Twin-SAM V8.0 (30deg probe tilt) - 2124	HBBL600-10000V6220420-1, 2025-December-19	EX3DV4 - SN7896, 2025-12-11	DAE4 Sn1724, 2025-03-14

Scan Setup

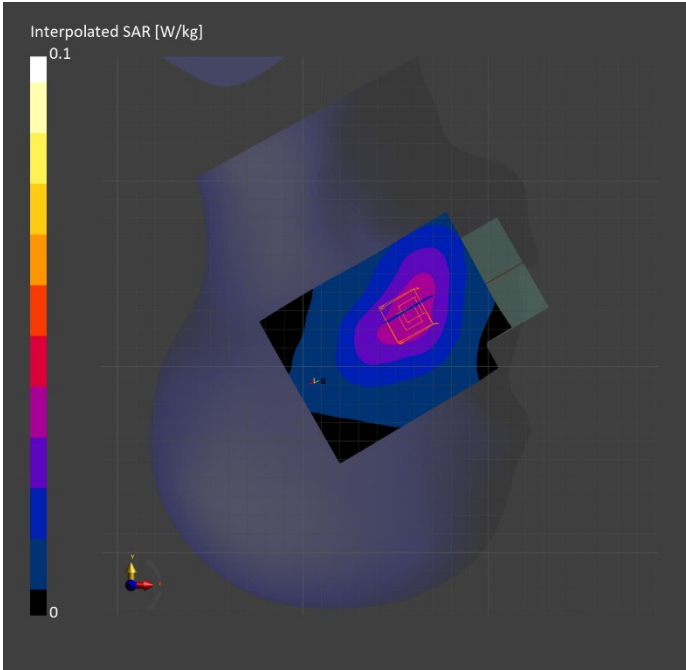
	Area Scan	Zoom Scan
Grid Extents [mm]	90.0 x 120.0	30.0 x 30.0 x 30.0
Grid Steps [mm]	15.0 x 15.0	6.0 x 6.0 x 1.5
Sensor Surface [mm]	3.0	1.4
Graded Grid	N/A	Yes
Grading Ratio	N/A	1.5
MAIA	Y	Y
Surface Detection	VMS + 6p	VMS + 6p
Scan Method	Measured	Measured

Measurement Results

	Area Scan	Zoom Scan
Date	2025-12-19, 15:37	2025-12-19, 15:47
psSAR1g [W/kg]	0.035	0.036
psSAR10g [W/kg]	0.024	0.028
Power Drift [dB]	0.07	0.15
Power Scaling	Disabled	Disabled
Scaling Factor [dB]		
TSL Correction	No correction	No correction
M2/M1 [%]		90.3
Dist 3dB Peak [mm]		22.5

Warning(s) / Error(s)

Details	Area Scan	Zoom Scan
Warning(s)		
Error(s)		



Test Plot 16#:Measurement Report for LTE Band 12, BACK, Band 12, UID 10175 CAH, Channel 23095 (707.500MHz)

Device under Test Properties

Model, , Manufacturer	Dimensions [mm]	IMEI	DUT Type
V200	136.0 x 56.0 x 8.0		4G Feature Phone

Exposure Conditions

Phantom Section, TSL	Position, Test Distance [mm]	Band	Group, UID	Frequency [MHz], Channel Number	Conversion Factor	TSL Conductivity [S/m]	TSL Permittivity
Flat, HSL	BACK, 5.00	Band 12	LTE-FDD, 10175-CAH	707.500, 23095	9.4	0.899	42.6

Hardware Setup

Phantom	TSL, Measured Date	Probe, Calibration Date	DAE, Calibration Date
Twin-SAM V8.0 (30deg probe tilt) - 2124	HBBL600-10000V6220420-1, 2025-December-19	EX3DV4 - SN7896, 2025-12-11	DAE4 Sn1724, 2025-03-14

Scan Setup

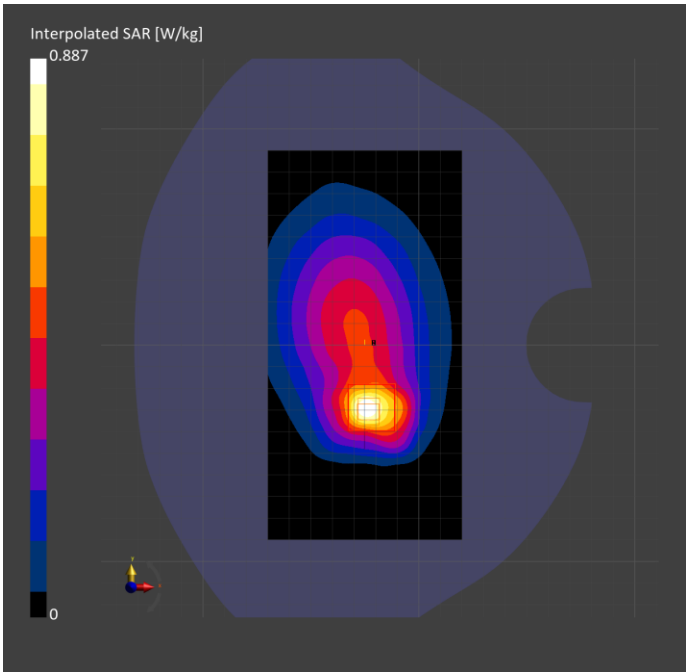
	Area Scan	Zoom Scan
Grid Extents [mm]	90.0 x 180.0	30.0 x 30.0 x 30.0
Grid Steps [mm]	15.0 x 15.0	6.0 x 6.0 x 1.5
Sensor Surface [mm]	3.0	1.4
Graded Grid	N/A	Yes
Grading Ratio	N/A	1.5
MAIA	N/A	N/A
Surface Detection	All points	All points
Scan Method	Measured	Measured

Measurement Results

	Area Scan	Zoom Scan
Date	2025-12-19, 23:48	2025-12-19, 00:02
psSAR1g [W/kg]	0.304	0.319
psSAR10g [W/kg]	0.182	0.170
Power Drift [dB]	0.08	-0.06
Power Scaling	Disabled	Disabled
Scaling Factor [dB]		
TSL Correction	No correction	No correction
M2/M1 [%]		61.5
Dist 3dB Peak [mm]		7.6

Warning(s) / Error(s)

Details	Area Scan	Zoom Scan
Warning(s)		
Error(s)		



Test Plot 17#:Measurement Report for LTE Band 41, CHEEK, Band 41, UID 10172 CAH, Channel 40640 (2593.000MHz)

Device under Test Properties

Model, Manufacturer	Dimensions [mm]	IMEI	DUT Type
V2000	136.0 x 56.0 x 14.0		4G Feature Phone

Exposure Conditions

Phantom Section, TSL	Position, Test Distance [mm]	Band	Group, UID	Frequency [MHz], Channel Number	Conversion Factor	TSL Conductivity [S/m]	TSL Permittivity
RightHead, HSL	CHEEK, 0.00	Band 41	LTE-TDD, 10172-CAH	2593.000, 40640	7.0	1.974	40.1

Hardware Setup

Phantom	TSL, Measured Date	Probe, Calibration Date	DAE, Calibration Date
Twin-SAM V8.0 (30deg probe tilt) - 2124	HBBL600-10000V6220420-1, 2025-December-27	EX3DV4 - SN7896, 2025-12-11	DAE4 Sn1724, 2025-03-14

Scan Setup

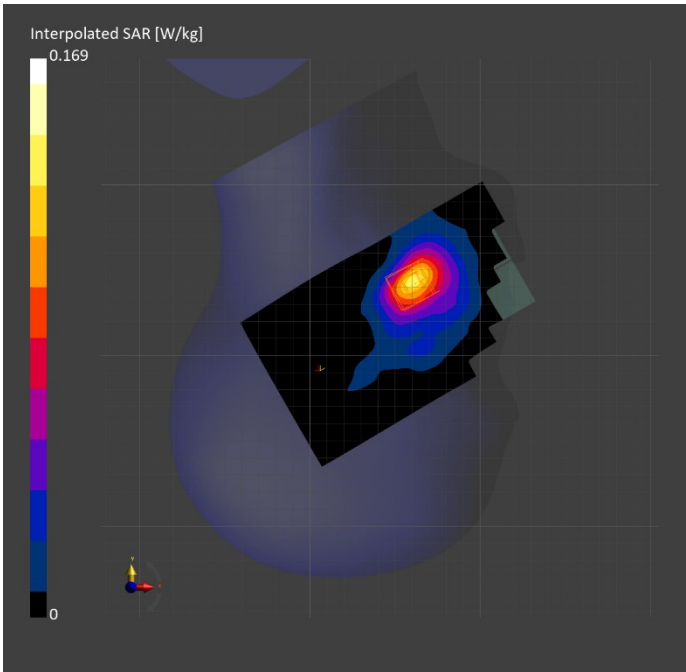
	Area Scan	Zoom Scan
Grid Extents [mm]	100.0 x 180.0	30.0 x 30.0 x 30.0
Grid Steps [mm]	10.0 x 10.0	5.0 x 5.0 x 1.5
Sensor Surface [mm]	3.0	1.4
Graded Grid	N/A	Yes
Grading Ratio	N/A	1.5
MAIA	Y	Y
Surface Detection	VMS + 6p	All points
Scan Method	Measured	Measured

Measurement Results

	Area Scan	Zoom Scan
Date	2025-12-27, 16:07	2025-12-27, 16:26
psSAR1g [W/kg]	0.104	0.113
psSAR10g [W/kg]	0.052	0.070
Power Drift [dB]	-0.06	0.04
Power Scaling	Disabled	Disabled
Scaling Factor [dB]		
TSL Correction	No correction	No correction
M2/M1 [%]		89.6
Dist 3dB Peak [mm]		10.6

Warning(s) / Error(s)

Details	Area Scan	Zoom Scan
Warning(s)		
Error(s)		



Test Plot 18#:Measurement Report for LTE Band 41, BACK, Band 41, UID 10172 CAH, Channel 40640 (2593.000MHz)

Device under Test Properties

Model, Manufacturer	Dimensions [mm]	IMEI	DUT Type
V2000	136.0 x 56.0 x 14.0		4G Feature Phone

Exposure Conditions

Phantom Section, TSL	Position, Test Distance [mm]	Band	Group, UID	Frequency [MHz], Channel Number	Conversion Factor	TSL Conductivity [S/m]	TSL Permittivity
Flat, HSL	BACK, 5.00	Band 41	LTE-TDD, 10172-CAH	2593.000, 40640	7.0	1.974	40.1

Hardware Setup

Phantom	TSL, Measured Date	Probe, Calibration Date	DAE, Calibration Date
Twin-SAM V8.0 (30deg probe tilt) - 2124	HBBL600-10000V6220420-1, 2025-December-27	EX3DV4 - SN7896, 2025-12-11	DAE4 Sn1724, 2025-03-14

Scan Setup

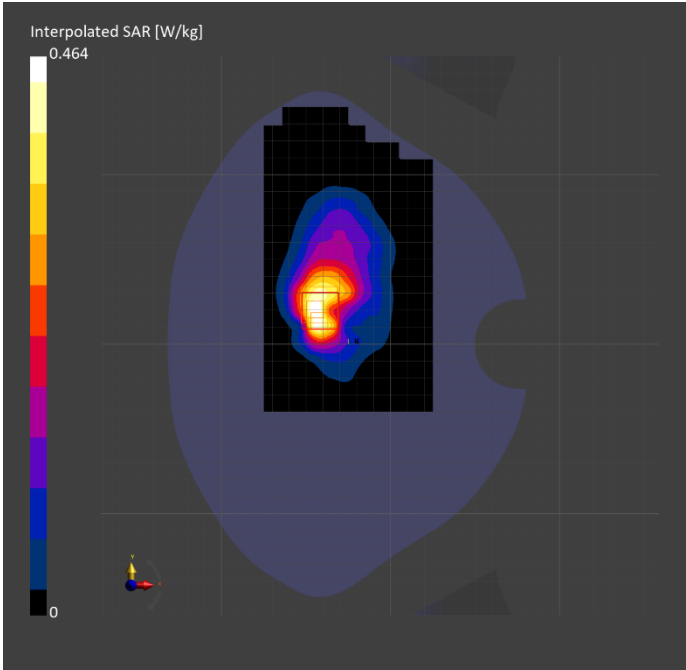
	Area Scan	Zoom Scan
Grid Extents [mm]	100.0 x 180.0	30.0 x 30.0 x 30.0
Grid Steps [mm]	10.0 x 10.0	5.0 x 5.0 x 1.5
Sensor Surface [mm]	3.0	1.4
Graded Grid	N/A	Yes
Grading Ratio	N/A	1.5
MAIA	Y	Y
Surface Detection	All points	All points
Scan Method	Measured	Measured

Measurement Results

	Area Scan	Zoom Scan
Date	2025-12-27, 07:17	2025-12-27, 07:34
psSAR1g [W/kg]	0.210	0.230
psSAR10g [W/kg]	0.108	0.118
Power Drift [dB]	0.10	0.08
Power Scaling	Disabled	Disabled
Scaling Factor [dB]		
TSL Correction	No correction	No correction
M2/M1 [%]		79.8
Dist 3dB Peak [mm]		7.3

Warning(s) / Error(s)

Details	Area Scan	Zoom Scan
Warning(s)		
Error(s)		



Test Plot 19#:Measurement Report for LTE Band 66, CHEEK, Band 66, UID 10169 CAF, Channel 132322 (1745.000MHz)

Device under Test Properties

Model, Manufacturer	Dimensions [mm]	IMEI	DUT Type
V2000	136.0 x 56.0 x 14.0		4G Feature Phone

Exposure Conditions

Phantom Section, TSL	Position, Test Distance [mm]	Band	Group, UID	Frequency [MHz], Channel Number	Conversion Factor	TSL Conductivity [S/m]	TSL Permittivity
RightHead, HSL	CHEEK, 0.00	Band 66	LTE-FDD, 10169-CAF	1745.000, 132322	7.89	1.351	41.4

Hardware Setup

Phantom	TSL, Measured Date	Probe, Calibration Date	DAE, Calibration Date
Twin-SAM V8.0 (30deg probe tilt) - 2124	HBBL600-10000V6220420-1, 2025-December-23	EX3DV4 - SN7896, 2025-12-11	DAE4 Sn1724, 2025-03-14

Scan Setup

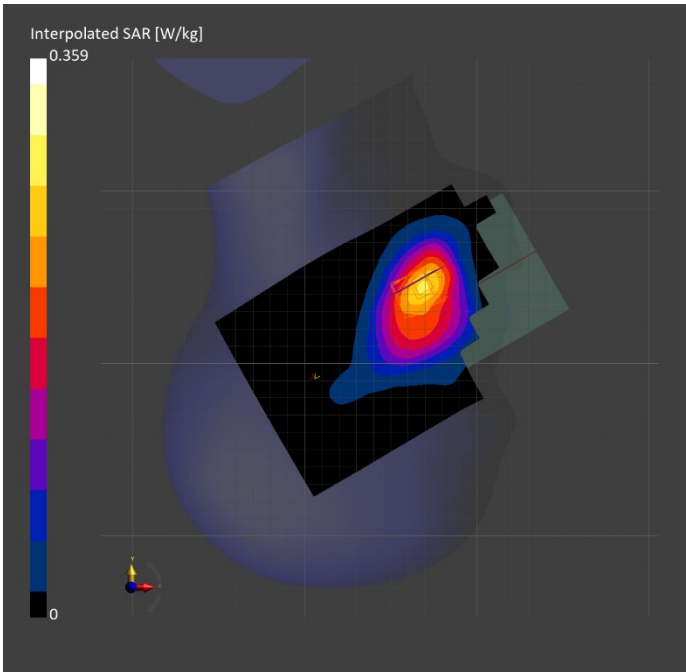
	Area Scan	Zoom Scan
Grid Extents [mm]	120.0 x 210.0	30.0 x 30.0 x 30.0
Grid Steps [mm]	15.0 x 15.0	6.0 x 6.0 x 1.5
Sensor Surface [mm]	3.0	1.4
Graded Grid	N/A	Yes
Grading Ratio	N/A	1.5
MAIA	N/A	N/A
Surface Detection	VMS + 6p	All points
Scan Method	Measured	Measured

Measurement Results

	Area Scan	Zoom Scan
Date	2025-12-23, 15:38	2025-12-23, 15:54
psSAR1g [W/kg]	0.227	0.255
psSAR10g [W/kg]	0.136	0.185
Power Drift [dB]	0.06	0.15
Power Scaling	Disabled	Disabled
Scaling Factor [dB]		
TSL Correction	No correction	No correction
M2/M1 [%]		88.1
Dist 3dB Peak [mm]		13.4

Warning(s) / Error(s)

Details	Area Scan	Zoom Scan
Warning(s)		
Error(s)		



Test Plot 20#:Measurement Report for LTE Band 66, BACK, Band 66, UID 10169 CAF, Channel 132572 (1770.000MHz)

Device under Test Properties

Model , Manufacturer	Dimensions [mm]	IMEI	DUT Type
LTE Band 66	136.0 x 56.0 x 14.0		4G Feature Phone

Exposure Conditions

Phantom Section, TSL	Position, Test Distance [mm]	Band	Group, UID	Frequency [MHz], Channel Number	Conversion Factor	TSL Conductivity [S/m]	TSL Permittivity
Flat, HSL	BACK, 5.00	Band 66	LTE-FDD, 10169-CAF	1770.000, 132572	7.89	1.391	41.1

Hardware Setup

Phantom	TSL, Measured Date	Probe, Calibration Date	DAE, Calibration Date
Twin-SAM V8.0 (30deg probe tilt) - 2124	HBBL600-10000V6220420-1, 2025-December-23	EX3DV4 - SN7896, 2025-12-11	DAE4 Sn1724, 2025-03-14

Scan Setup

	Area Scan	Zoom Scan
Grid Extents [mm]	90.0 x 120.0	30.0 x 30.0 x 30.0
Grid Steps [mm]	15.0 x 15.0	6.0 x 6.0 x 1.5
Sensor Surface [mm]	3.0	1.4
Graded Grid	N/A	Yes
Grading Ratio	N/A	1.5
MAIA	N/A	N/A
Surface Detection	All points	All points
Scan Method	Measured	Measured

Measurement Results

	Area Scan	Zoom Scan
Date	2025-12-23, 00:42	2025-12-23, 01:11
psSAR1g [W/kg]	0.950	0.941
psSAR10g [W/kg]	0.573	0.550
Power Drift [dB]	-0.12	0.01
Power Scaling	Disabled	Disabled
Scaling Factor [dB]		
TSL Correction	No correction	No correction
M2/M1 [%]		74.2
Dist 3dB Peak [mm]		10.8

Warning(s) / Error(s)

Details	Area Scan	Zoom Scan
Warning(s)		
Error(s)		

